



NITFS Compliance Registration



Product: Enterprise Image Access Solutions (E-IAS) Image Chipper Version 1.1 (Linux)

Sponsor: DTI Visual Information Solutions

Developer: Visual Information Solutions

Date: 20 April 2010
Expiration: 19 April 2012
Registration #: 3015

☒ Initial Registration
Supplemental/Update # _____
☐ Derived from Reg. # _____

System
N-0105/98, §4.1.1

NITFS Features Implemented:

Product
N-0105/98, §4.1.2

☒ **Component**
N-0105/98, §4.1.3

Complexity Level							
NITF 2.1 CLEVEL							
	3	5	6	7			
Interpret							
Generate							
NITF 2.0 CLEVEL							
	1	2	3	4	5	6	Other
Interpret							
Generate							

Configurations Tested:

- VMWave workstation, Fedora, kernel Linux, GNOME

Note: The image chipper performs a limited interpretation on the input products to process an update compliant output product. An example is interpreting the RPC TRE to establish new IGEOLO corner points. The application also updates DIGEST, ICHIP and HISTO TREs

Format
☒ NITF
☒ 2.1
☒ 2.0
☐ 1.1
☐ NSIF
☐ 1.0

Pixel Value Types
☐ Boolean
☒ Integer
☐ Signed Integer *
☐ IEEE Real *
☐ IEEE Complex *

Annotation Segment Types
☐ Bit Mapped **
☐ CGM, 2301
☐ CGM, 2301A
☐ Labels **

Text Segments
☐ STA
☐ UT1
☐ U8S
☐ MTF

Image Segment Types
☒ MONO
☒ RGB
☐ RGB/LUT
☒ YCbCr
☒ MULTI
☐ NO DISPLAY
☐ POLAR

Image Compression
☒ No Compression
☒ JPEG Lossy, 8-bit
☒ JPEG Lossy, 12-bit
☐ JPEG Downsampling
☐ JPEG Lossless
☒ JPEG 2000
☐ Bi-Level
☐ Vector Quantization

Data Extension Segments
☐ TRE_OVERFLOW
☐ STREAMING_FILE_HEADER
☐ Controlled Extensions **
☐ Registered Extensions **

Tagged Record Extensions
☒ DE
☒ DIGEST
☐ PTAE
☒ KLRA
☒ HIPB
☒ CDRD

Legend
Interpret
Generate
☒ Fully implemented
☒ Partially implemented
☐ Not implemented

Valerie Baker, Lt Col, USAF, Portfolio Chief
Joint Interoperability Test Command
Executive Agent to National Geospatial-
Intelligence Agency for the NITFS Test and
Evaluation Program

Registration does not guarantee that a product will meet all users' requirements.
Potential users should evaluate the detailed test results to determine the suitability of
the product for the intended use. Optional NITFS features may not be implemented.